



# DMDT9922

## PNP DUAL, MATCHED PAIR SURFACE MOUNT TRANSISTOR

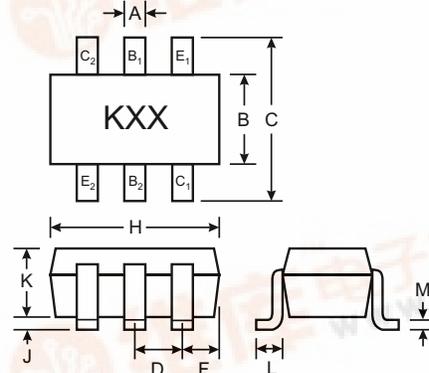
ADVANCE INFORMATION

### Features

- Epitaxial Planar Die Construction
- Low Noise
- High Current Gain
- Matched Pair of Transistors

### Mechanical Data

- Case: SOT-363, Molded Plastic
- Terminals: Solderable per MIL-STD-202, Method 208
- Terminal Connections: See Diagram
- Marking: K3S
- Weight: .006 grams (approx.)



SOT-363		
Dim	Min	Max
A	0.10	0.30
B	1.15	1.35
C	2.00	2.20
D	0.65 Nominal	
F	0.30	0.40
H	1.80	2.20
J	—	0.10
K	0.90	1.00
L	0.25	0.40
M	0.10	0.25
All Dimensions in mm		

### Maximum Ratings @ T<sub>A</sub> = 25°C unless otherwise specified

Characteristic	Symbol	DMDT9922	Unit
Collector-Base Voltage	V <sub>CB0</sub>	-50	V
Collector-Emitter Voltage	V <sub>CE0</sub>	-40	V
Emitter-Base Voltage	V <sub>EB0</sub>	-5.0	V
Collector-Collector Voltage	V <sub>CC0</sub>	-50	V
Emitter-Emitter Voltage	V <sub>EE0</sub>	-50	V
Collector Current - Continuous (Note 1)	I <sub>C</sub>	-100	mA
Power Dissipation (Note 1)	P <sub>d</sub>	200	mW
Thermal Resistance, Junction to Ambient (Note 1)	R <sub>θJA</sub>	625	K/W
Operating and Storage and Temperature Range	T <sub>J</sub> , T <sub>STG</sub>	-55 to +125	°C



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**Electrical Characteristics** @  $T_A = 25^\circ\text{C}$  unless otherwise specified

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
<b>OFF CHARACTERISTICS (Note 2)</b>						
Collector-Base Breakdown Voltage	$V_{(BR)CBO}$	-50	—	—	V	$I_C = -50\mu\text{A}, I_E = 0$
Collector-Emitter Breakdown Voltage	$V_{(BR)CEO}$	-40	—	—	V	$I_C = -1.0\text{mA}, I_B = 0$
Emitter-Base Breakdown Voltage	$V_{(BR)EBO}$	-5.0	—	—	V	$I_E = -50\mu\text{A}, I_C = 0$
Collector-Base Leakage Current	$I_{CBO}$	—	-0.3	-500	nA	$V_{CB} = -30\text{V}$
Emitter-Base Leakage Current	$I_{EBO}$	—	—	-500	nA	$V_{EB} = -4.0\text{V}$
Collector-Emitter Leakage Current	$I_{CES}$	—	-4	-1000	nA	$V_{CE} = -40\text{V}$
<b>ON CHARACTERISTICS (Note 2)</b>						
DC Current Gain	$h_{FE}$	300	450	555	—	$I_C = -1.0\text{mA}, V_{CE} = -6.0\text{V}$
Collector-Emitter Saturation Voltage	$V_{CE(SAT)}$	—	-0.1	-0.5	V	$I_C = -50\text{mA}, I_B = -5.0\text{mA}$
	$V_{CE(SAT)}$	—	-0.1	—	V	$I_C = -1\text{mA}, I_B = -0.1\text{mA}$
Base-Emitter Impedance	$r_{be}$	—	-0.5	—	$\Omega$	$I_C = -10\mu\text{A}$ to $-1\text{mA}$
Emitter-Base Offset Voltage	$V_{OS}$	—	10	—	$\mu\text{V}$	$V_{CB} = 0\text{V}, I_C = -1\mu\text{A}$ to $-1\text{mA}$
Change in Emitter-Base Offset Voltage vs. Collector-Base Voltage (CMRR)	$\frac{\Delta V_{OS}}{\Delta V_{CB}}$	—	10	—	$\mu\text{V}$	$V_{CB} = 0\text{V}, I_C = -1\mu\text{A}$ to $-1\text{mA}$
Change in Emitter-Base Offset Voltage vs. Collector-Current	$\frac{\Delta V_{OS}}{\Delta I_C}$	—	5	—	$\mu\text{V}$	$V_{CB} = 0\text{V}, I_C = -10\mu\text{A}$ to $-1\text{mA}$
Average Offset Voltage Drift	$TC V_{OS}$	—	0.5	—	$\mu\text{V}/^\circ\text{C}$	$I_C = -10\mu\text{A}$ to $-1\text{mA}$
Emitter-Base Offset Current	$I_{OS}$	—	8	—	nA	$I_C = -10\mu\text{A}, V_{CB} = 0\text{V}$
Change in Emitter-Base Offset Current vs. Collector-Base Voltage	$\frac{\Delta I_{OS}}{\Delta V_{CB}}$	—	30	—	nA	$V_{CB} = 0$ to $-50\text{V}$
Average Offset Current Drift	$TC I_{OS}$	—	50	—	$\text{pA}/^\circ\text{C}$	$I_C = -10\mu\text{A}$
Collector-Collector Leakage Current	$I_{CC}$	—	35	—	pA	$V_{CE} = -40\text{V}$
<b>SMALL SIGNAL CHARACTERISTICS</b>						
Output Capacitance	$C_{obo}$	—	-4	15	pF	$V_{CB} = -10\text{V}, f = 1.0\text{MHz}, I_E = 0$
Input Capacitance	$C_{ibo}$	—	—	70	pF	$V_{EB} = -0.5\text{V}, I_C = 0, f = 1\text{MHz}$
Output Conductance	$h_{OE}$	—	10	—	$\mu\text{S}$	$I_C = -1\text{mA}, V_{CE} = -5\text{V}$
Current Gain-Bandwidth Product	$f_T$	—	170	—	MHz	$V_{CE} = -12\text{V}, I_C = -2.0\text{mA}, f = 100\text{MHz}$

- Notes: 1. Valid provided that terminals are kept at ambient temperature.  
2. Pulse test: Pulse width  $\leq 300\mu\text{s}$ , duty cycle  $\leq 2\%$ .

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